

# INTERNATIONAL STANDARD

**IEC**  
**60749-34**

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## **Semiconductor devices – Mechanical and climatic test methods –**

### **Part 34: Power cycling**



Reference number  
IEC 60749-34:2004(E)

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INTERNATIONAL ELECTROTECHNICAL COMMISSION

**SEMICONDUCTOR DEVICES –  
MECHANICAL AND CLIMATIC TEST METHODS –**

**Part 34: Power cycling**

FOREWORD

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International Standard IEC 60749-34 has been prepared by IEC technical committee 47: Semiconductor devices.

This standard cancels and replaces IEC/PAS 62206 published in 2000. This first edition constitutes a technical revision.

The text of this standard is based on the following documents:

FDIS	Report on voting
47/1738/FDIS	47/1748/RVD

Full information on the voting for the approval of this standard can be found in the report on voting indicated in the above table.

This publication has been drafted in accordance with the ISO/IEC Directives, Part 2.

The committee has decided that the contents of this publication will remain unchanged until 2007. At this date, the publication will be

- reconfirmed;
- withdrawn;
- replaced by a revised edition, or
- amended